Tomographic Profiling with Energy Dispersive X-Ray Scattering

M. Croft, I. Zakharchenko, Y. Gulak, T. Tsakalakos, M. Dasilva (Rutgers Univ.), Z. Zhong, J. Hu, J. Hastings (NSL S), and R. Holtz (NRL) Beamline(s): X17B1, X17C

We have been implementing energy disperssive x-ray diffraction (EDXRD) methods for profiling residual strains in structural composite materials (e.g. ceramic coated steel). A number of useful tomographic–like profiling (via x-ray scattering) techniques have been developed as part of this work. In this profiling the incident/diffracted beam and sampling volume are fixed, while the sample is scanned through the scattering micro-volume. The Bragg reflection energies (E) and the inter-atomic-plane spacing (dhkl) are related by E(keV) = 6.199/ dhkl sin(θ) where 2θ is the constant scattering angle. A high-resolution energy-dispersive-Ge detector collects the EDXRD spectra. Figure 1 illustrates some typical EXRD spectra: of the steel and WC/Co coating portions of one of our composites; and of a aluminatitania coating, on steel (inset).

Figure 2 shows a scattered intensity profile (SIP) for a ~200µm plasma sprayed WC/Co coating on a 2.8 mm steel-blank. For the SIP, the net scattered intensity (at all energies) is monitored versus sample position. The steel-substrate and WC/Co-coating are clearly differentiated by virtue of the much higher scattering strength of the high-Z W. In Figure 2-bottom a still more powerful tagged-scattered-intensity-profile (TSIP) method is illustrated for a steel-WC/Co-coated composite. For the TSIP's full EDXRD spectra are collected, versus

specimen position, allowing steel- and WC-specific spectral-features to be "tagged" and integrated separately. Such intensity integration of tagged lines (grouped by lattice-structure/chemical-compound/prefered-crystallite-orientation) provides contrast highlighting of these properties in the tomograph-like profile.

In Figure 3 a reflection geometry scattering schematic is shown, along with a reflection SIP of an alumina-titania coated steel substrate. Points 1-4 in the figure correspond to: (1) the onset of scattering at the ceramic surface; (2) the ceramic interior scattering, with a weak exponential depth-decay; (3) the rapid rise of the scattering at the higher-Z, steel interface; and (4) the rapid exponential decay of scattering in the steel, due to strong absorption.

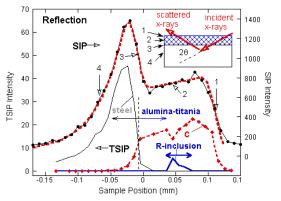


Figure 3. (left) A reflection-mode SIP (solid line) for an alumnia-titania coated steel specimen along with a reflection scattering geometry schematic (inset). The dashed red line is a simple scattering-absorption model for a coating thickness of 124 \pm 1 μm . The numbered points are discussed in the text. Also, the separate reflection-mode TSIP curves for steel-scattering, and rhombohedral-(R)- and cubic-(C)-alumina-scattering.

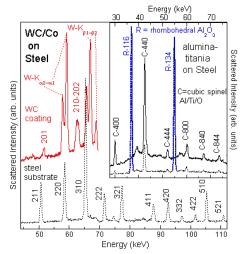


Figure 1. EDXRD spectra for the steel and WC-coating potions of composite specimen. Inset: spectra for an aluminatitania coating with varying mixtures of cubic (C) and rhombohedral (R) Al₂O₃.

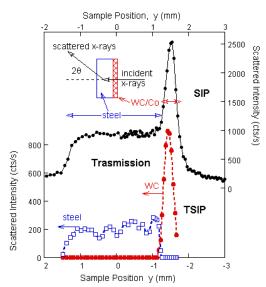


Figure 2.(right) A SIP for a WC/Co coated steel specimen with inset transmission schematic. Also, the "tagged"-SIP (TSIP) spectra for a second WC/Co coated steel specimen